

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		RULE 53(b) DIVISION OF APPLICATION NO. 10/267,834	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Takuroh OZAWA et al.			
				FILING DATE July 24 2003		GROUP	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
J.L.		5,714,838	2-1998	HAIGHT et al.		
		6,072,450	6-2000	YAMADA et al.		
		5,587,329	12-96	HSEUH et al.		
		5,828,429	10-98	TAKEMURA		
		6,023,307	02-00	TAKEMURA		
		5,670,792	09-97	UTSUGI et al.		
		6,011,529	01-00	IKEDA		
		5,995,073	11-99	ISAMI et al.		
		6,243,069	06-01	OGAWA et al.		
	J.Y.		5,869,929	02-99	EIDA et al.	

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
J.L.		EP-A1-0 653 741	05-95	Europe		
		JP-A-8-129358	05-96	Japan		
		JP 8-227276	09-96	Japan		
		JP 08 241057 A	09-96	Japan		
		EP 0112 700 A	07-84	Japan		
		WO 96 06456 A	02-96	WIPO		
		JP 08 129360 A	05-96	Japan		
		EP 0717 439 A	06-96	Europe		
J.L.		JP 08-241057 (translation only)	9-96	Japan		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
J.L.	Alan G. Lewis, et al., <u>Physical Mechanisms For Short Channel Effects In Polysilicon Thin Film Transistors</u> , IEEE, 1989, pgs. 13.4.1-13.4.4
J.L.	Alan G. Lewis et al., <u>Polysilicon TFT Circuit Design and Performance</u> , IEEE Journal of Solid-State Circuits, December 1992, Vol. 27, No. 12, pgs. 1833-1842.

EXAMINER <i>Jean Degervance</i>	DATE CONSIDERED 6-9-05
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Date: July 24, 2003

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
J.L.	1	5,786,796	07/1998	TAKAYAMA et al.	345	76	
J.L.	2	5,986,632	11/1999	TAKAYAMA et al.	345	99	
J.L.	3	5,463,279	10/1995	KHORMAEI	315	169.3	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
J.L.	4	EP 0 653 741 A1	05/1995	EUROPE			
J.L.	5	JP 08-241057 (w/ English abstract)	09/1996	JAPAN			
J.L.	6	WO 96/06456	02/1996	WIPO			
J.L.	7	EP 0 112 700	07/1984	EUROPE			
J.L.	8	JP 08-129360 (w/ English abstract)	05/1996	JAPAN			
J.L.	9	EP 0 717 439 A2	06/1996	EUROPE			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
J.L.	10	Lewis A. G. et al.: "Polysilicon TFT Circuit Design and Performance", IEEE Journal of Solid-State Circuits, IEEE Inc. New York, US, Vol. 27, No. 12, 1 December 1992					
J.L.	11	Lewis A. G. et al.: "Physical Mechanisms for Short Channel Effects in Polysilicon Thin Film Transistors", Proceedings of the International Electron Devices Meeting. Washington, Dec. 3-6, 1989, New York, IEEE, US					
EXAMINER <i>Cham Kuyenance</i>				DATE CONSIDERED 6-9-05			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: October 24, 2003

Form PTO-1449
(REV. 8-83)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
100629.03APPLICATION NO.
10/625,617

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Tokuroh OZAWA et al.FILING DATE
July 24, 2003

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	5,463,279	10/1995	KHORMAEI	315	169.03

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
J.L. JP-A-9-106887 (w/ Eng. Abstract)	04/1997	JAPAN	—	—
J.L. JP-A-10-12377 (w/ Eng. Abstract)	01/1998	JAPAN	—	—
J.L. EP 0 880 303 A1	11/1998	EUROPE	—	—
J.L. EP 0 849 721 A2	06/1998	EUROPE	—	—
J.L. EP 0 961 525 A1	12/1999	EUROPE	—	—

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

Jean Dupont

DATE CONSIDERED

6-9-05

Examiner:

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Date: November 6, 2003

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 100629.03		APPLICATION NO. 10/625,617	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Tokuroh OZAWA et al.			
				FILING DATE July 24, 2003		GROUP 2674	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
J-L.	1	JP 04-161984 (Eng. Abstr Only)	06/05/1992	JAPAN	A		
J-L.	2	JP 08-129359(Eng.Trans&Abstr)	05/21/1996	JAPAN	A		
J-L.	3	JP 09-016123(Eng.Trans&Abstr)	01/17/1997	JAPAN	A		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER <i>Dean Key</i>				DATE CONSIDERED <i>6-9-05</i>			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: June 10, 2004 ✓

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(REV. 8-83)U.S. Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
100629.03APPLICATION NO.
10/625,617

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Tokuroh OZAWA et al.FILING DATE
July 24, 2003GROUP
2674

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
J.L.	1	JP 05-313195 (w/English-language translation)	11/26/1993	JAPAN		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

John Key - ce

DATE CONSIDERED

6-9-05

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: February 9, 2005